IFW

Patent

THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Keiji YADA, et al.) Re: Information Disclosure) Statement

Serial No.: 10/719,008) Group: not yet assigned

Filed: November 21, 2003) Examiner: not yet assigned

) Our Ref: B-5309 621525-5

For: "X-RAY MICROSCOPIC INSPECTION

APPARATUS"

) Date: November 10, 2004

Commissioner for Patents P.O. Box 1450 Alexandria VA, 22313-1450

NOV 1 5 2004

Sir:

In accordance with the Applicants' duty to disclose information which may be material to the examination of this application, the undersigned respectfully requests that the Examiner consider on the merits the documents listed on the enclosed Form PTO-1449 (modified) before issuing the first Office Action on the merits. We are enclosing herewith a copy of each document listed on the enclosed Form PTO-1449 (modified).

The documents listed on the enclosed Form PTO-1449 (modified) include those cited in the European Search Report for a related European Patent Application No. EP 04001489.6. A copy of the Search Report (11 pages) is enclosed herewith.

The filing of this Information Disclosure Statement (IDS) shall not be construed as a representation that a search has been made (37 C.F.R. 1.97(g)), an admission that the information cited is, or is considered to be, material to patentability, or that no other material information exists.

The Applicants believe that this IDS is being submitted before the issuance of a first Office Action on the merits and before the issuance of a Final Rejection or Notice of Allowance. Therefore,

Information Disclosure Statement USSN 10/719,008 November 10, 2004 Page 2

no official fees should be due; and this IDS should be considered on the merits. If this IDS is being submitted after the issuance of the first Office Action on the merits and before the issuance of a Final Rejection or Notice of Allowance, please contact the undersigned to authorize a payment of \$180.00 (or any other required amount), which is the fee set forth in 37 C.F.R. § 1.97(c), if the Examiner believes that such a fee is due in order for this IDS to be considered on the merits.

The filing of this Information Disclosure Statement shall not be construed as an admission against interest in any manner. (Notice of January 9, 1992, 1135 O.G. 13-25, at 25.)

The person making this statement is the practitioner who signs below on the basis of information supplied by an individual associated with the filing and prosecution of this application (37 C.F.R. § 1.56(c)) and on the basis of information in the practitioner's file.

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first-class mail in an envelope addressed to the "Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450",

on November 10, 2004 by Shana Morda.

Respectfully submitted,

Robert Popa

Attorney for Applicant

Reg. No. 43,010

LADAS & PARRY 5670 Wilshire Boulevard Suite 2100 Los Angeles, CA 90036 (323) 934-2300

Enclosures: Form PTO-1449 (modified) (1 page)

Copy of Search Report for EP 04001489.6 (11 pages)
Copy of documents listed on Form PTO-1449 (modified)

Information disclosure Statement US\$1,10/719,008
November 10, 2004
Page 3

Form PTO-1449 (Modified)	ATTY DOCKET NO. B-5309 621525-5	U.S. SERIAL NO. 10/719,008	
LIST OF PATENTS AND PUBLICATIONS	APPLICANTS Keiji YADA, et al.		
STATEMENT	FILING DATE November 21, 2003	GROUP not yet assigned	

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	ISSUE DATE	NAME	CLASS	SUB- CLASS	FILING DATE or 102(e) DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO
865,050	4/1961	GB			
2 131 224	6/1984	GB			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Delong, A., et al., "A New Design Of Field Emission Electron Gun With A Magnetic Lens," Optik, Vol. 81, No. 3, pp. 103-108 (1989).

Mayo, S.C., et al., "X-Ray Phase-Contrast Microscopy and Microtomography," Optics Express, Vol. 11, No. 19, pp. 2289-2302 (September 2, 2003).

EXAMINER	DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.